

SN74ALVC16543
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

JANUARY 1993

- Member of the Texas Instruments Widebus™ Family
- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Designed to Facilitate Incident Wave Switching for Line Impedances of $50\ \Omega$ or Greater
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ C$
- Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ C$
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model ($C = 200\ pF$, $R = 0$)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Package Options Include Plastic 300-mil Shrink Small-Outline and Thin Shrink Small-Outline Packages

description

This 16-bit registered transceiver is designed for 2.7-V to 3.6-V V_{CC} operation.

The SN74ALVC16543 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate latch-enable (LEAB or LEBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable (CEAB) input must be low in order to enter data from A or to output data from B. If CEAB is low and LEAB is low, the A-to-B latches are transparent; a subsequent low-to-high transition of LEAB puts the A latches in the storage mode. With CEAB and OEAB both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar but requires using the CEBA, LEBA, and OEBA inputs.

The SN74ALVC16543 is packaged in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN74ALVC16543 is characterized for operation from $-40^\circ C$ to $85^\circ C$.

DGG OR DL PACKAGE (TOP VIEW)		
1OEAB	1	56
1LEAB	2	55
1CEAB	3	54
GND	4	53
1A1	5	52
1A2	6	51
V_{CC}	7	50
1A3	8	49
1A4	9	48
1A5	10	47
GND	11	46
1A6	12	45
1A7	13	44
1A8	14	43
2A1	15	42
2A2	16	41
2A3	17	40
GND	18	39
2A4	19	38
2A5	20	37
2A6	21	36
V_{CC}	22	35
2A7	23	34
2A8	24	33
GND	25	32
2CEAB	26	31
2LEAB	27	30
2OEAB	28	29
2OEBA		

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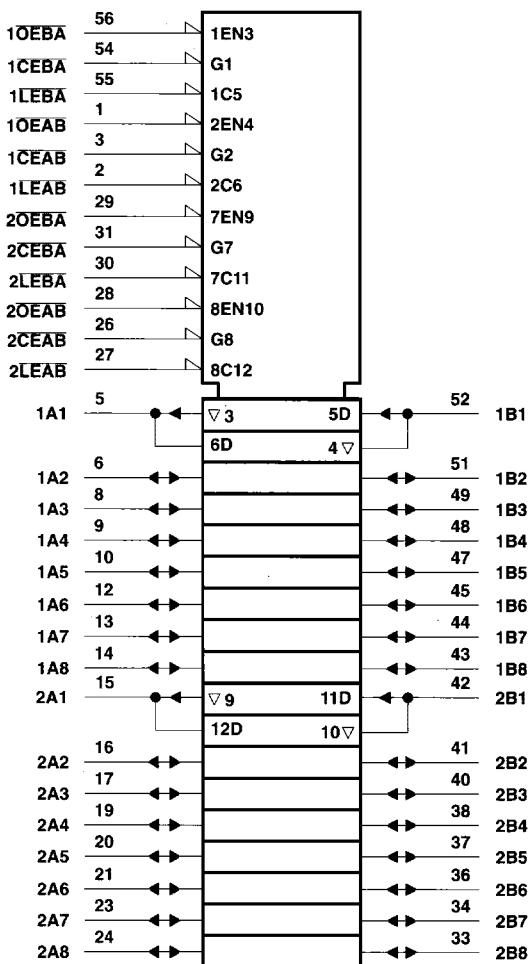
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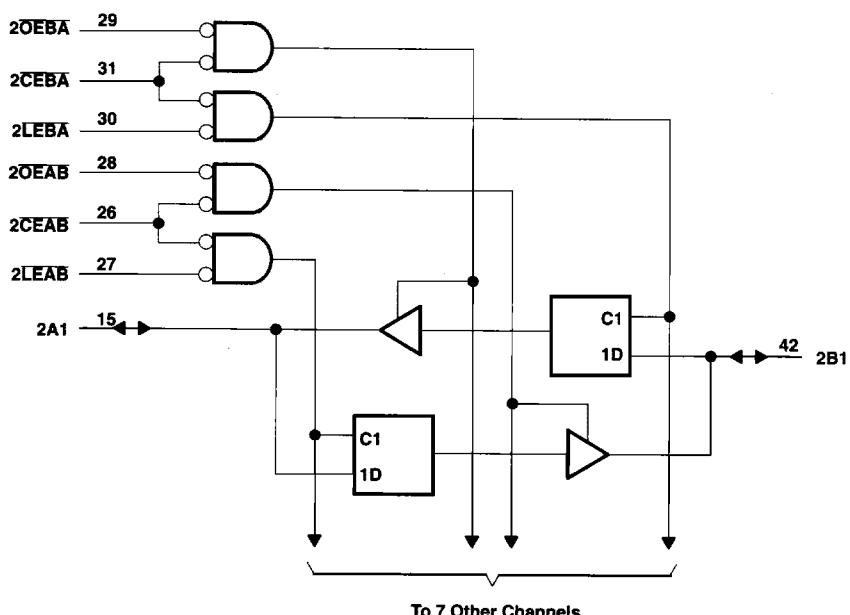
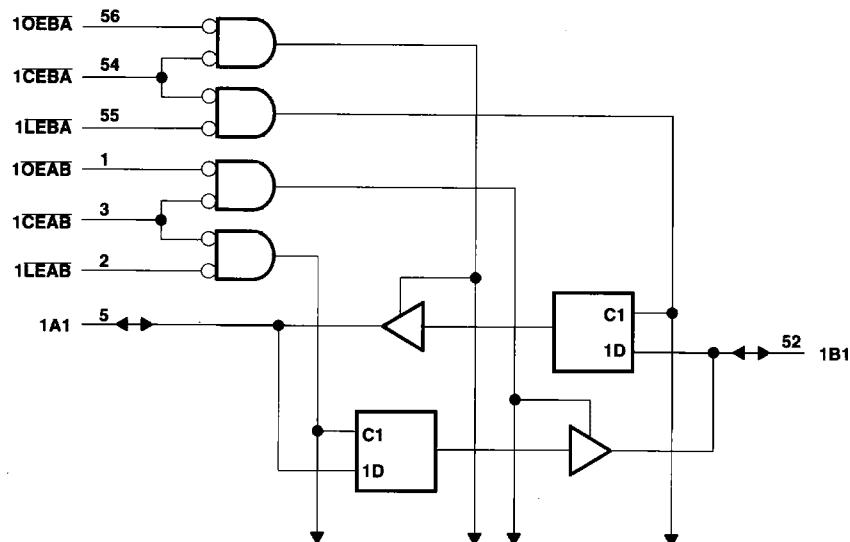
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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FUNCTION TABLE†
 (each 8-bit section)

INPUTS				OUTPUT B
CEAB	LEAB	OEAB	A	
H	X	X	X	Z
X	X	H	X	Z
L	H	L	X	B ₀ ‡
L	L	L	L	L
L	L	L	H	H

† A-to-B data flow is shown; B-to-A flow control is the same except that it uses CEBA, LEBA, and OEBA.

‡ Output level before the indicated steady-state input conditions were established.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage range, V _{CC}	-0.5 V to 4.6 V
Input voltage range, V _I (except I/O ports) (see Note 1)	-0.5 V to 4.6 V
Input voltage range, V _I (I/O ports) (see Notes 1 and 2)	-0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Notes 1 and 2)	-0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	-50 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I _O (V _O = 0 to V _{CC})	±50 mA
Continuous current through V _{CC} or GND pins	±100 mA
Maximum power dissipation at T _A = 55°C (in still air): DGG package	0.7 W
DL package	1 W
Storage temperature range	-65°C to 150°C

§ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This value is limited to 4.6 V maximum.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	2.7	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 2.7 V to 3.6 V	2	V
V _{IL}	Low-level input voltage	V _{CC} = 2.7 V to 3.6 V	0.8	V
V _I	Input voltage	0	V _{CC}	V
V _O	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 2.7 V V _{CC} = 3 V	-12 -24†	mA
I _{OL}	Low-level output current	V _{CC} = 2.7 V V _{CC} = 3 V	12 24†	mA
Δt/Δv	Input transition rise or fall rate	0	10	ns/V
T _A	Operating free-air temperature	-40	85	°C

NOTE 3: Unused or floating pins (input or I/O) must be held high or low.

† Current duty cycle ≤ 50%, f ≥ 1 kHz

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC} [†]	MIN	TYP	MAX	UNIT
V _{IK}		I _I = -18 mA	2.7 V			-1.2	V
V _{OH}		I _{OH} = -100 µA	MIN to MAX	V _{CC} -0.2			V
		I _{OH} = -12 mA		2.7 V	2.2		
		I _{OH} = -24 mA		3 V	2.4		
V _{OL}		I _{OL} = 100 µA	MIN to MAX			0.2	V
		I _{OL} = 12 mA		2.7 V		0.4	
		I _{OL} = 24 mA		3 V		0.55	
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _{OZ} [‡]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			20	µA
ΔI _{CC}		V _{CC} = 3 V to 3.6 V, Other inputs at V _{CC} or GND	One input at V _{CC} - 0.6 V,			500	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		TBD		pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		TBD		pF

[†] For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

